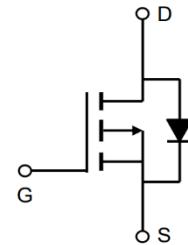


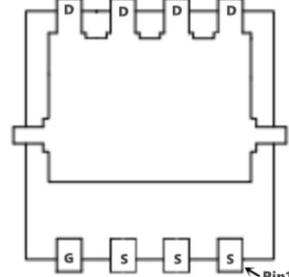
-30V P-Channel Enhancement Mode MOSFET
Description

The AP70P03DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.


General Features

$V_{DS} = -30V$ $I_D = -70A$

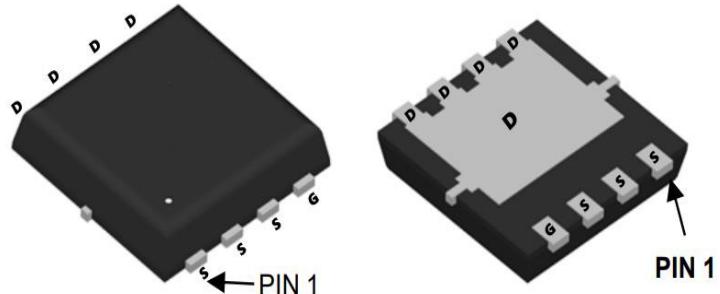
$R_{DS(ON)} < 8.0m\Omega$ @ $V_{GS} = -10V$ (Type: 5.8m Ω)


Application

Lithium battery protection

Wireless impact

Mobile phone fast charging


Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP70P03DF	PDFN3*3-8L	AP70P03DF XXX YYYY	5000

Absolute Maximum Ratings (TC=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	-30	V
VGS	Gate-Source Voltage	± 20	V
ID@TC=25°C	Continuous Drain Current, VGS @ -10V1	-70	A
ID@TC=100°C	Continuous Drain Current, VGS @ -10V1	-57	A
IDM	Pulsed Drain Current2	-200	A
EAS	Single Pulse Avalanche Energy3	125	mJ
IAS	Avalanche Current	-40	A
PD@TC=25°C	Total Power Dissipation4	69	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R _{θJA}	Thermal Resistance Junction-Ambient 1	85	°C/W
R _{θJC}	Thermal Resistance Junction-Case1	1.6	°C/W

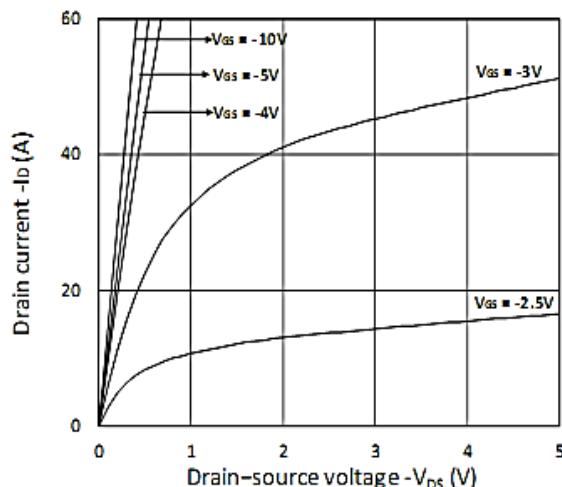
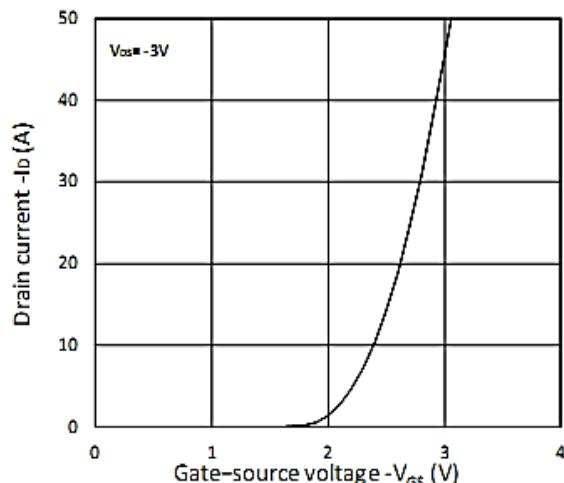
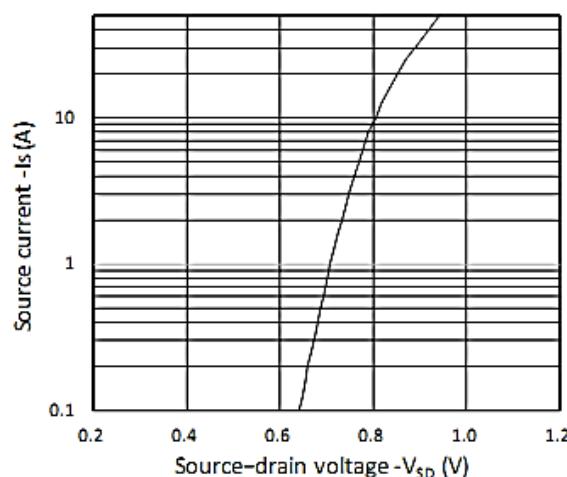
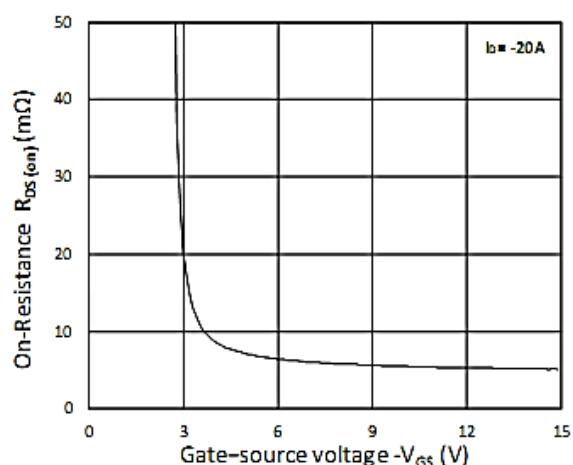
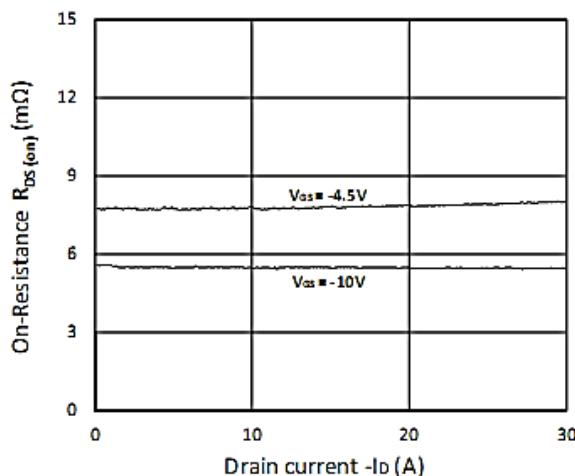
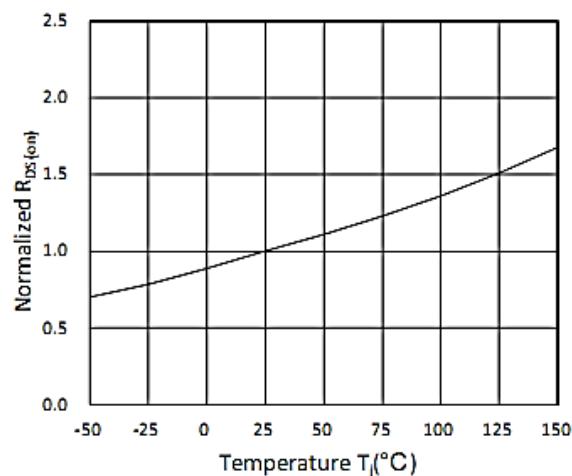


-30V P-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=-250\mu\text{A}$	-30	-34	---	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $I_D=-1\text{mA}$	---	-0.0232	---	$\text{V}/^{\circ}\text{C}$
$\text{RDS}(\text{ON})$	Static Drain-Source On-Resistance	$V_{\text{GS}}=-10\text{V}$, $I_D=-20\text{A}$	---	5.8	8.0	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_D=-15\text{A}$	---	8.0	11	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=-250\mu\text{A}$	-1.2	-1.4	-2.5	V
$\Delta V_{\text{GS(th)}}$	$V_{\text{GS(th)}}$ Temperature Coefficient		---	4.6	---	$\text{mV}/^{\circ}\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^{\circ}\text{C}$	---	---	-1	uA
		$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=55^{\circ}\text{C}$	---	---	-5	
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
gfs	Forward Transconductance	$V_{\text{DS}}=-5\text{V}$, $I_D=-30\text{A}$	---	30	---	S
R_g	Gate Resistance	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	9.8	---	Ω
Q_g	Total Gate Charge (-4.5V)	$V_{\text{DS}}=-15\text{V}$, $V_{\text{GS}}=-4.5\text{V}$ $I_D=-20\text{A}$	---	35	---	nC
Q_{gs}	Gate-Source Charge		---	9.9	---	
Q_{gd}	Gate-Drain Charge		---	10.5	---	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=-15\text{V}$, $V_{\text{GS}}=-10\text{V}$, $R_G=3.0\Omega$ $I_D=-20\text{A}$	---	10.8	---	ns
T_r	Rise Time		---	13.2	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	73	---	
T_f	Fall Time		---	35	---	
C_{iss}	Input Capacitance	$V_{\text{DS}}=-15\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	3520	---	pF
C_{oss}	Output Capacitance		---	465	---	
C_{rss}	Reverse Transfer Capacitance		---	370	---	
I_s	Continuous Source Current	$V_G=V_D=0\text{V}$, Force Current	---	---	-70	A
I_{SM}	Pulsed Source Current		---	---	-130	A
V_{SD}	Diode Forward Voltage	$V_{\text{GS}}=0\text{V}$, $I_s=-1\text{A}$, $T_J=25^{\circ}\text{C}$	---	---	-1.3	V
t_{rr}	Reverse Recovery Time	$I_F=-20\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25^{\circ}\text{C}$	---	25	---	nS
Q_{rr}	Reverse Recovery Charge		---	10	---	nC

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、The power dissipation is limited by 175°C junction temperature
- 4、EAS condition: $T_J=25^{\circ}\text{C}$, $V_{\text{DD}}= -24\text{V}$, $V_{\text{G}}= -10\text{V}$, $R_G=7\Omega$, $L=0.1\text{mH}$, $I_{\text{AS}}= -40\text{A}$
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

-30V P-Channel Enhancement Mode MOSFET
Typical Characteristics

Figure 1. Output Characteristics

Figure 2. Transfer Characteristics

Figure 3. Forward Characteristics of Reverse

Figure 4. $R_{DS(ON)}$ vs. V_{GS}

Figure 5. $R_{DS(ON)}$ vs. I_D

Figure 6. Normalized $R_{DS(ON)}$ vs. Temperature

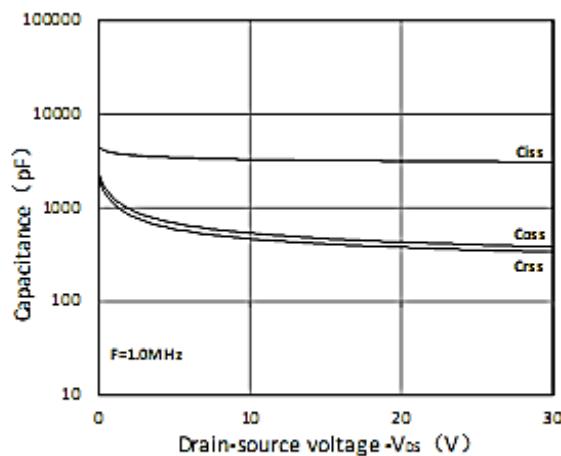
-30V P-Channel Enhancement Mode MOSFET


Figure 7. Capacitance Characteristics

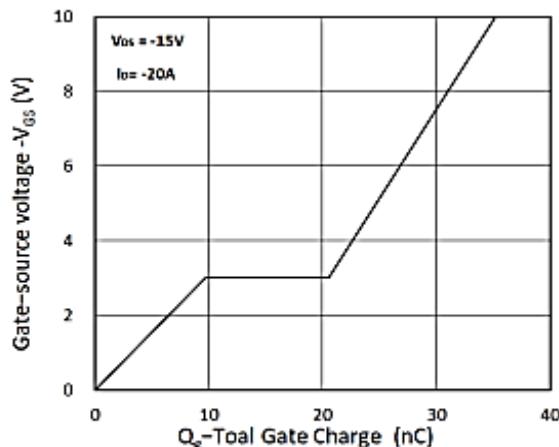


Figure 8. Gate Charge Characteristics

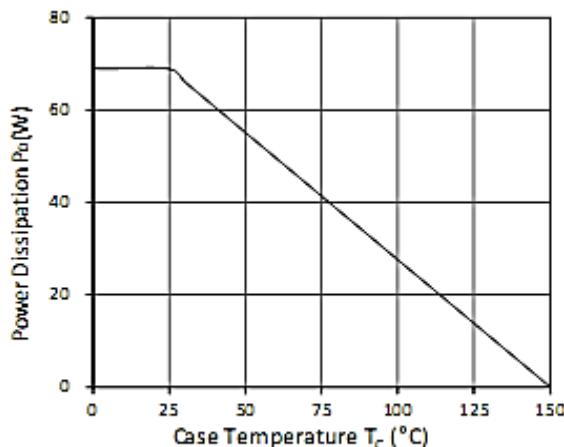


Figure 9. Power Dissipation

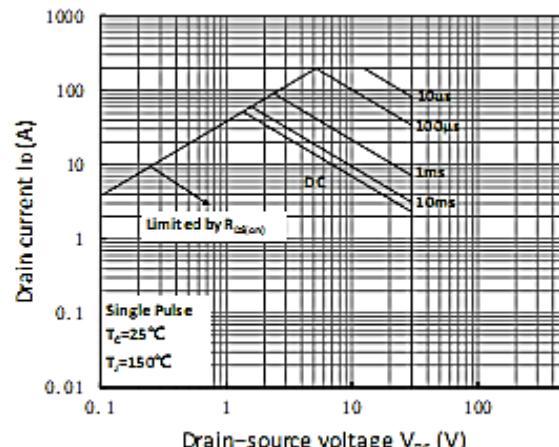


Figure 10. Safe Operating Area

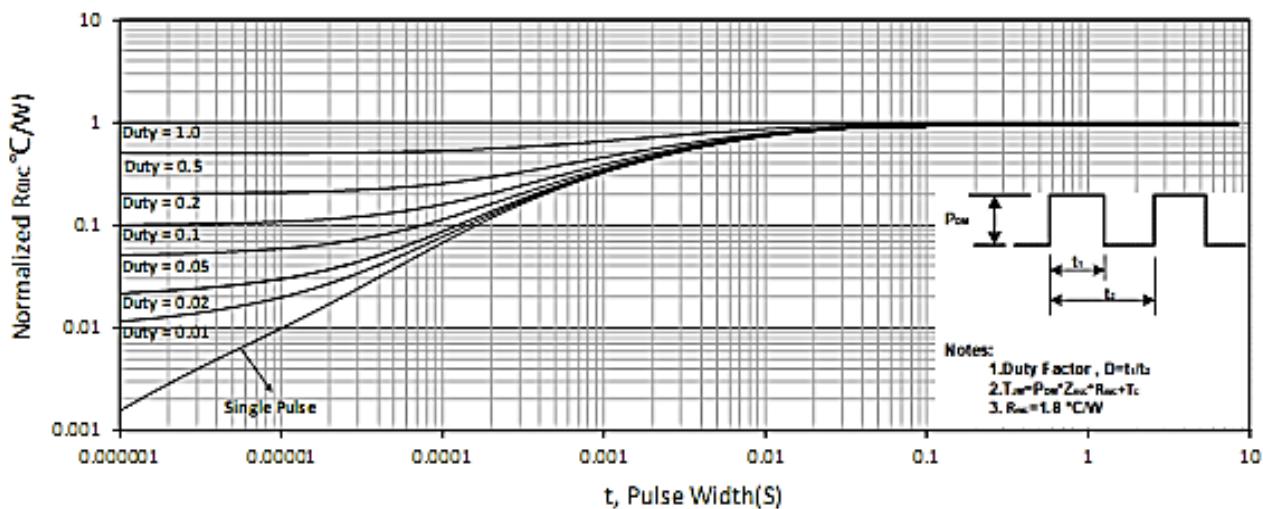
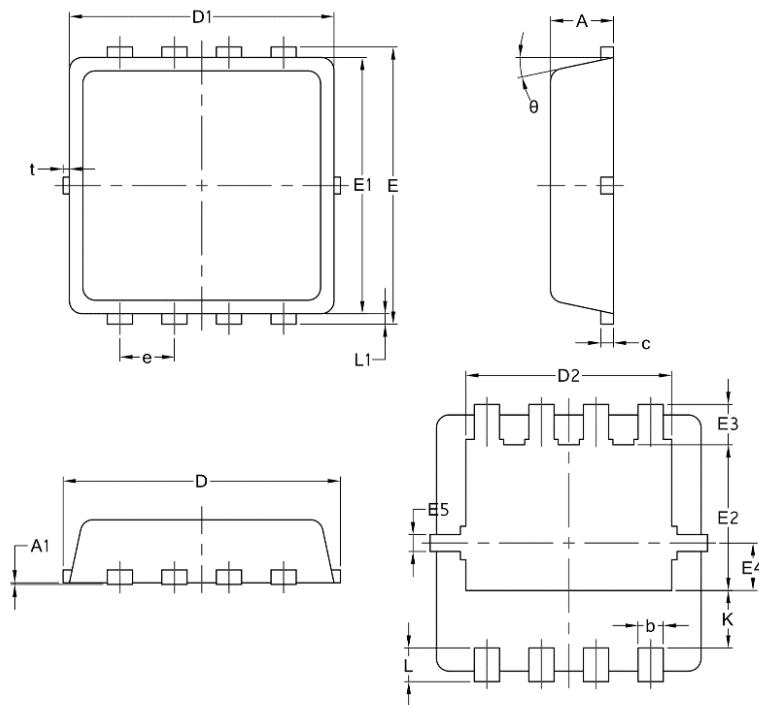


Figure 11. Normalized Maximum Transient Thermal Impedance

-30V P-Channel Enhancement Mode MOSFET
Package Mechanical Data-DFN3*3-8L-JQ Single



Symbol	Common		
	mm		
	Mim	Nom	Max
A	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
c	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14